

| ID | $R_{DS(ON)}$ (Typ) | VDSS |
|-----|--------------------|------|
| 30A | 120m Ω | 600V |

Applications:

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)
- AC-DC Switching Power Supply

Features:

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability

Ordering Information

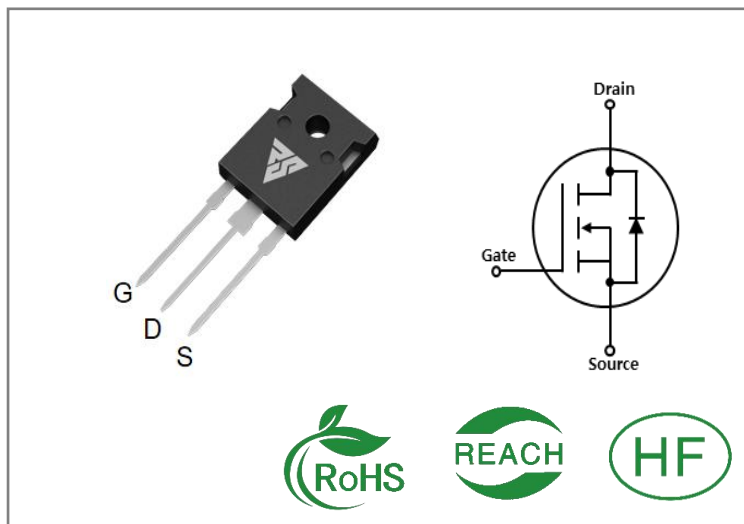
| Part Number | Package | Marking | Packing | Qty. |
|-------------|---------|-----------|---------|--------|
| RS60R130W | T0-247 | RS60R130W | Tube | 30 PCS |

Absolute Maximum Ratings $T_c = 25^\circ\text{C}$ unless otherwise specified

| Symbol | Parameter | RS60R130W | Units |
|-------------|--|------------|------------------|
| VDSS | Drain-to-Source Voltage | 600 | V |
| ID | Continuous Drain Current $T_C = 25^\circ\text{C}$ | 30 | A |
| ID | Continuous Drain Current $T_C = 100^\circ\text{C}$ | 19.5 | |
| IDM | Pulsed Drain Current (Note*1) | 90 | |
| PD | Power Dissipation | 162 | W |
| VGS | Gate- to- Source Voltage | ± 30 | V |
| EAS | Single Pulse Avalanche Energy $I_{AS} = 2\text{A}, V_{DD} = 50\text{V}, R_G = 25\ \Omega, T_C = 25^\circ\text{C}$ | 330 | mJ |
| dv/dt | MOSFET dv/ dt ruggedness $V_{DS} = 0 \dots 400\text{V}$ | 50 | V/ns |
| dv/dt | Reverse diode dv/dt $V_{DS} = 0 \dots 400\text{V}, T_j = 25^\circ\text{C}, I_{SD} \leq I_D$ | 15 | V/ns |
| TL TPKG | Maximum Temperature for Soldering | 300 260 | $^\circ\text{C}$ |
| | Leads at 0.063in(1.6mm)from Case for 10 seconds | | |
| | Package Body for 10 seconds | | |
| TJ and TSTG | Operating Junction and Storage Temperature Range | -55 to 150 | |

* Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" Table may cause permanent damage to the device.



Thermal Resistance

| Symbol | Parameter | RS60R130W | Units | Test Conditions |
|---------------|---------------------|-----------|-------------------------------|---|
| R θ JC | Junction-to-Case | 0.77 | $^{\circ}\text{C} / \text{W}$ | Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of + 1 5 0 $^{\circ}\text{C}$ |
| R θ JA | Junction-to-Ambient | 62.5 | | 1 cubic foot chamber, free air. |

OFF Characteristics $T_J = 25^{\circ}\text{C}$ unless otherwise specified

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--------|-------------------------------------|------|------|------|---------------|--|
| BVDSS | Drain- to- source Breakdown Voltage | 600 | -- | -- | V | $V_{GS}=0\text{V}, I_D=250\mu\text{A}$ |
| IDSS | Drain- to- Source Leakage Current | -- | -- | 1 | μA | $V_{DS}=600\text{V}, V_{GS}=0\text{V}$ |
| IGSS | Gate- to- Source Forward Leakage | -- | -- | 100 | nA | $V_{GS}=30\text{V}, V_{DS}=0\text{V}$ |
| | Gate- to- Source Reverse Leakage | -- | -- | -100 | | $V_{GS}=-30\text{V}, V_{DS}=0\text{V}$ |

ON Characteristics $T_J = 25^{\circ}\text{C}$ unless otherwise specified

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|---------|--|------|------|------|------------|-------------------------------------|
| RDS(on) | Static Drain- to- Source On-Resistance(Note*2) | -- | 120 | 130 | m Ω | $V_{GS}=10\text{V}, I_D=15\text{A}$ |
| VGS(TH) | Gate Threshold Voltage | 2 | -- | 4 | V | $V_{GS}=V_{DS}, I_D=250\mu\text{A}$ |

Resistive Switching Characteristics Essentially independent of operating temperature

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|---------|----------------------|------|------|------|-------|--|
| td(ON) | Turn- on Delay Time | -- | 30 | -- | nS | $V_{DS}=300\text{V}$ $I_D=30\text{A}$ $R_G=25\Omega$ |
| trise | Rise Time | -- | 45 | -- | | |
| td(OFF) | Turn- OFF Delay Time | -- | 145 | -- | | |
| tfall | Fall Time | -- | 36 | -- | | |

Dynamic Characteristics Essentially independent of operating temperature

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--------|---------------------------------|------|------|------|-------|-------------------------------|
| Ciss | Input Capacitance | -- | 1908 | -- | pF | VGS=0V VDS=50V f=400kHz |
| Coss | Output Capacitance | -- | 129 | -- | | |
| Crss | Reverse Transfer Capacitance | -- | 2.9 | -- | | |
| Qg | Total Gate Charge | -- | 50 | -- | nC | VDS=480V ID=30A VGS=10V |
| Qgs | Gate- to- Source Charge | -- | 10 | -- | | |
| Qgd | Gate-to-Drain(" Miller") Charge | -- | 14 | -- | | |

Source- Drain Diode Characteristics

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--------|---------------------------|------|------|------|-------|--------------------------------------|
| IS | Continuous Source Current | -- | -- | 30 | A | Integral pn- diode in MOSFET |
| ISM | Maximum Pulsed Current | -- | -- | 90 | A | |
| VSD | Diode Forward Voltage | -- | -- | 1.4 | V | IS=30A,VGS=0V |
| trr | Reverse Recovery Time | -- | 445 | -- | nS | VDD=100V IS=30A,di/dt=100A /μs |
| Qrr | Reverse Recovery Charge | -- | 6.4 | -- | μC | |

Notes:

- * 1. Repetitive rating,pulse width limited by maximum junction temperature.
- * 2. Pulse Test: Pulse width $\leq 300\mu s$, Duty Cycle $\leq 2\%$

Typical Feature Curve

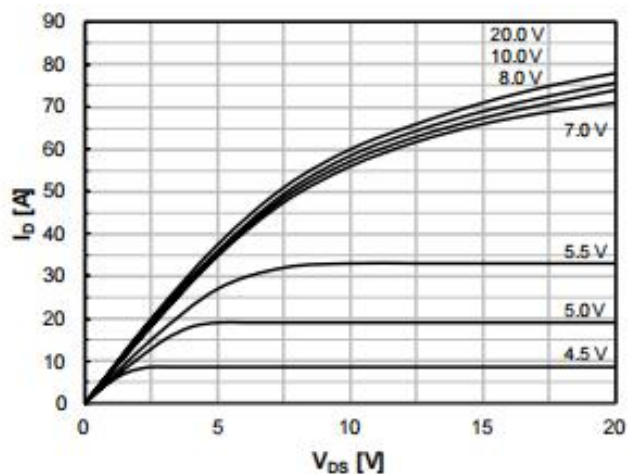


Fig. 1 Output Characteristics

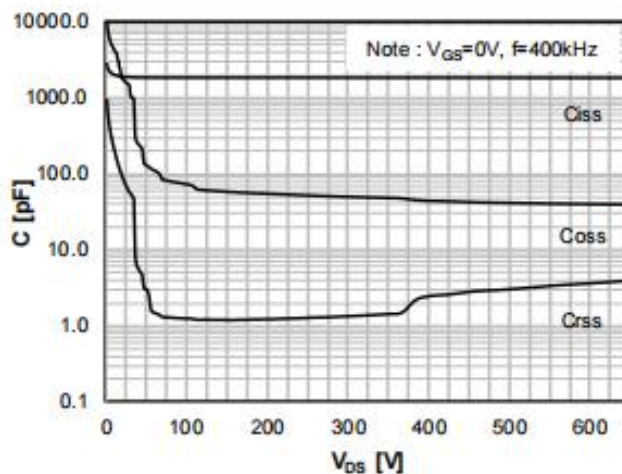


Fig. 2 Capacitances

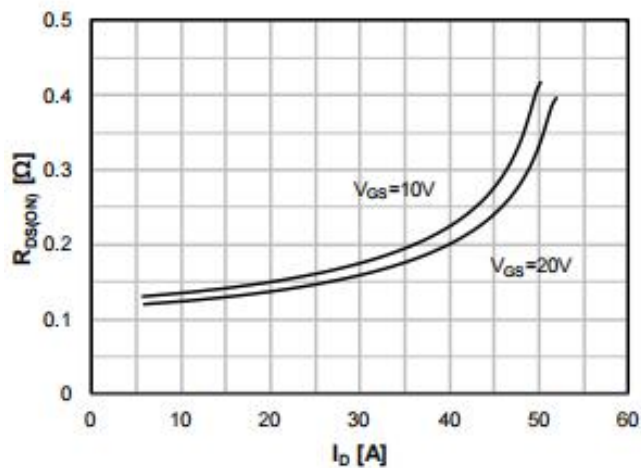


Fig. 3 On-state Resistance

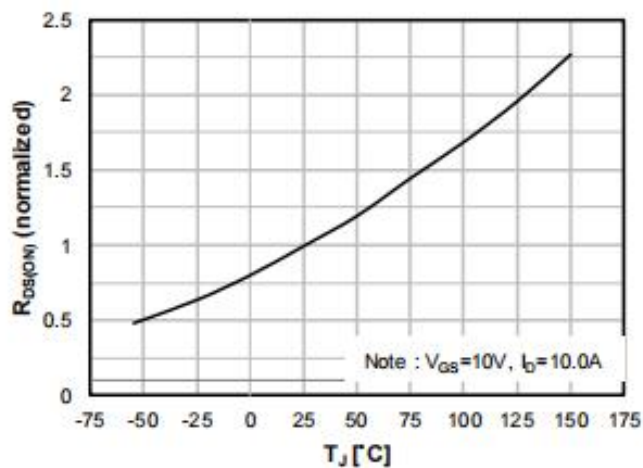


Fig. 4 On-state Resistance with Temperature

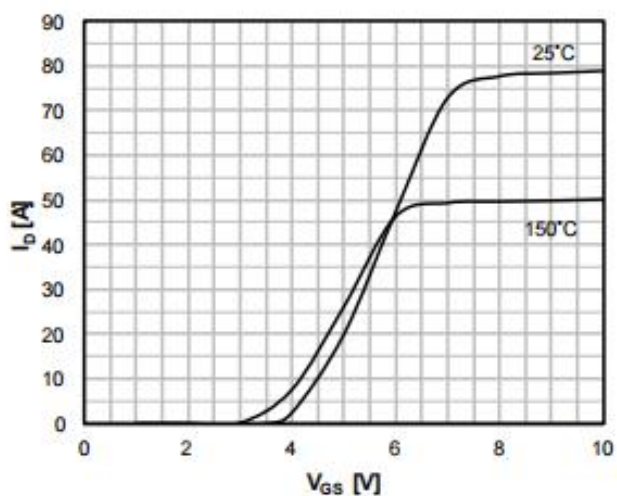


Fig 5. Transfer Characteristics

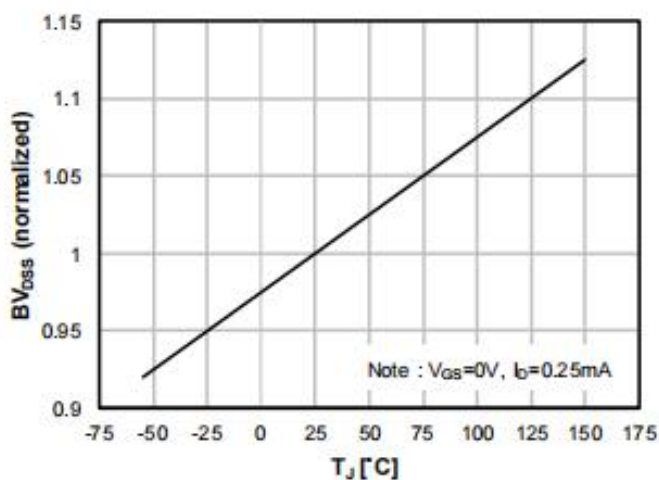


Fig 6. Breakdown Voltage with Temperature

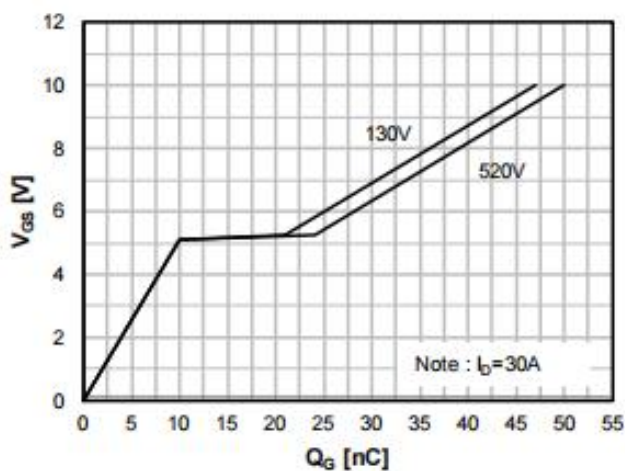


Fig 7. Gate Charge

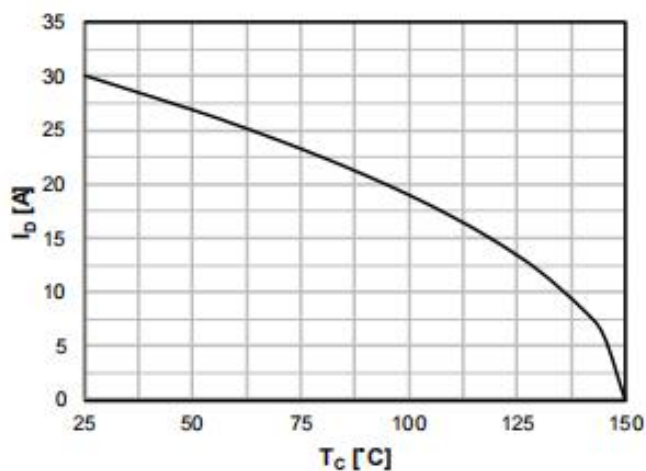


Fig 8. Maximum Drain Current

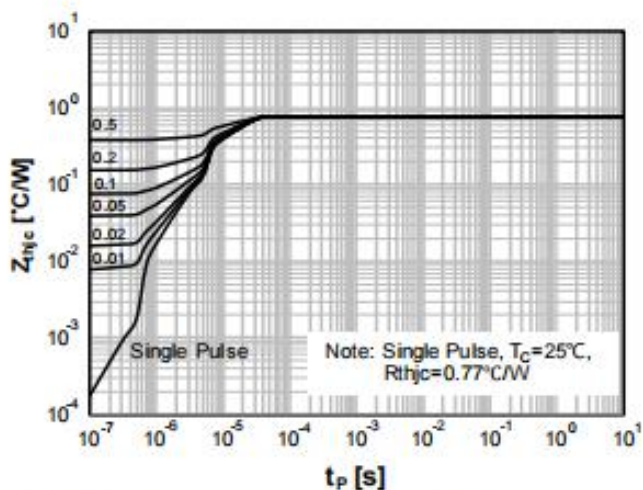


Fig 9. Maximum Transient Thermal Characteristics

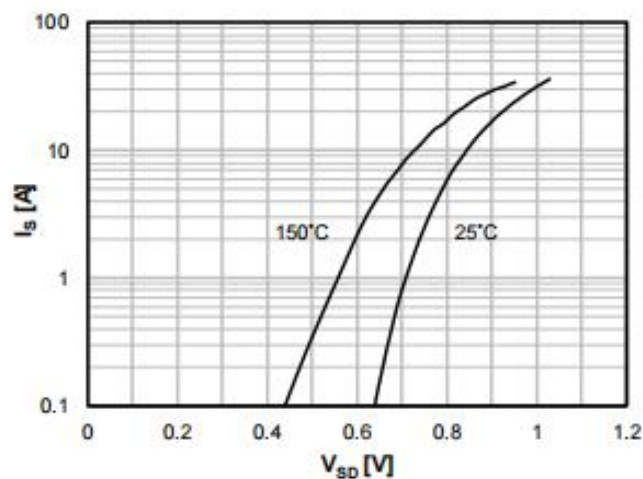


Fig 10. Body Diode Characteristics

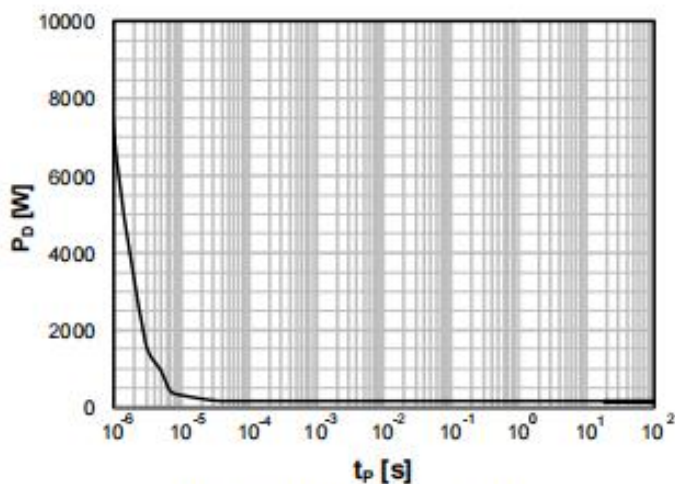


Fig 11. Power Dissipation

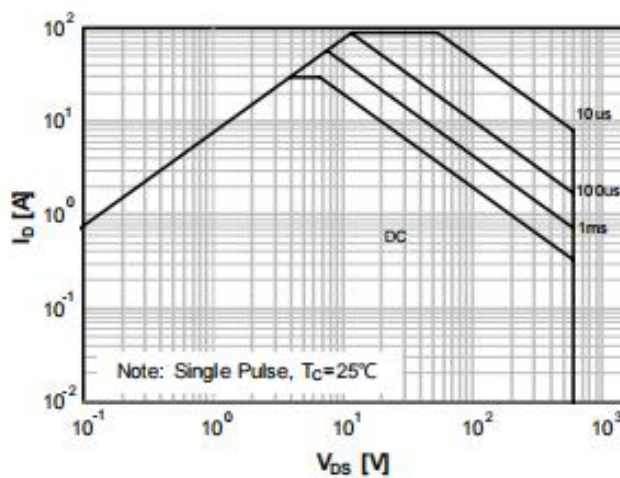


Fig 12. Safe Operating Area

Test Circuits and Waveforms

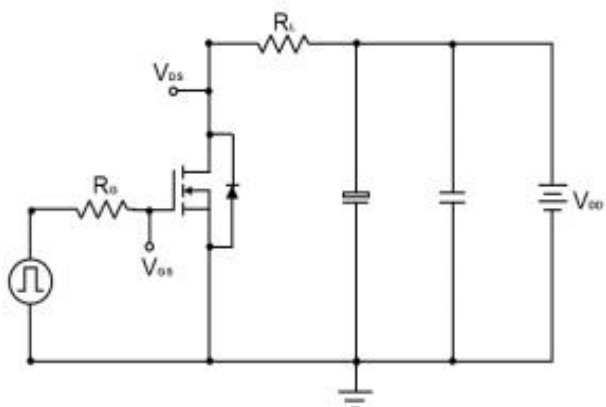


Fig 13. Test circuit for resistive load switching times

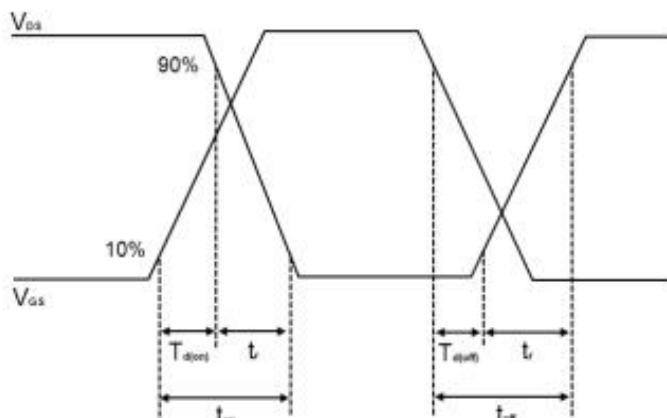


Fig 14. Switching times waveform

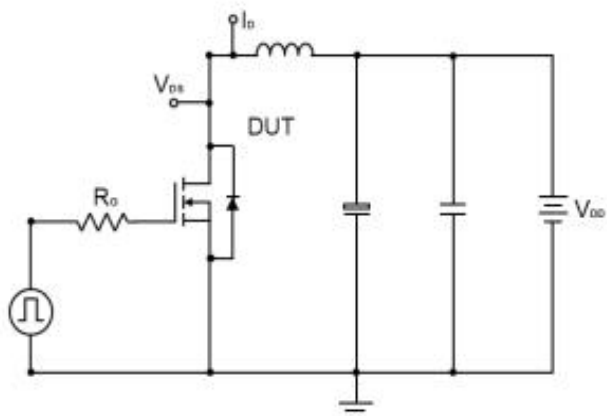


Fig 15. Test circuit for unclamped inductive load

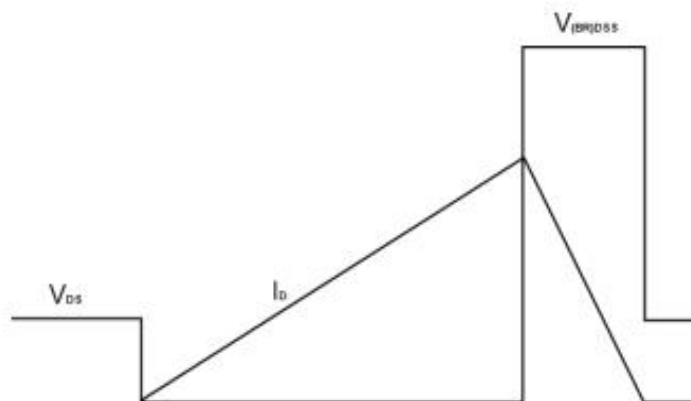


Fig 16. Unclamped inductive waveform

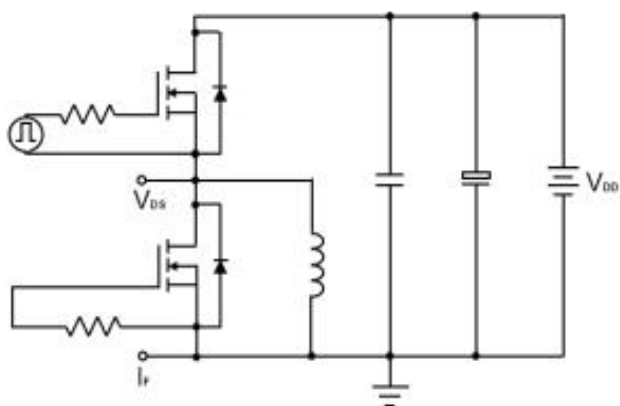


Fig 17. Test circuit for diode

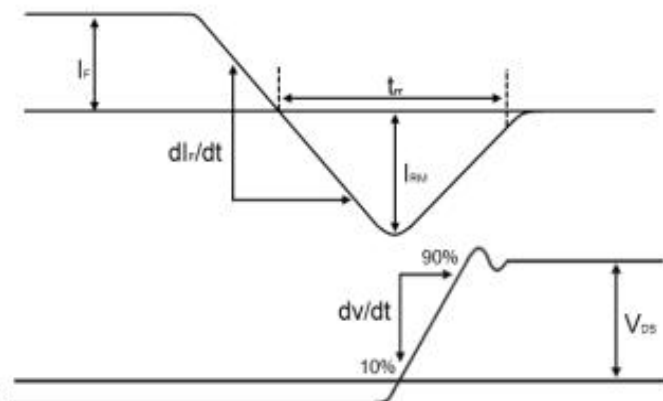
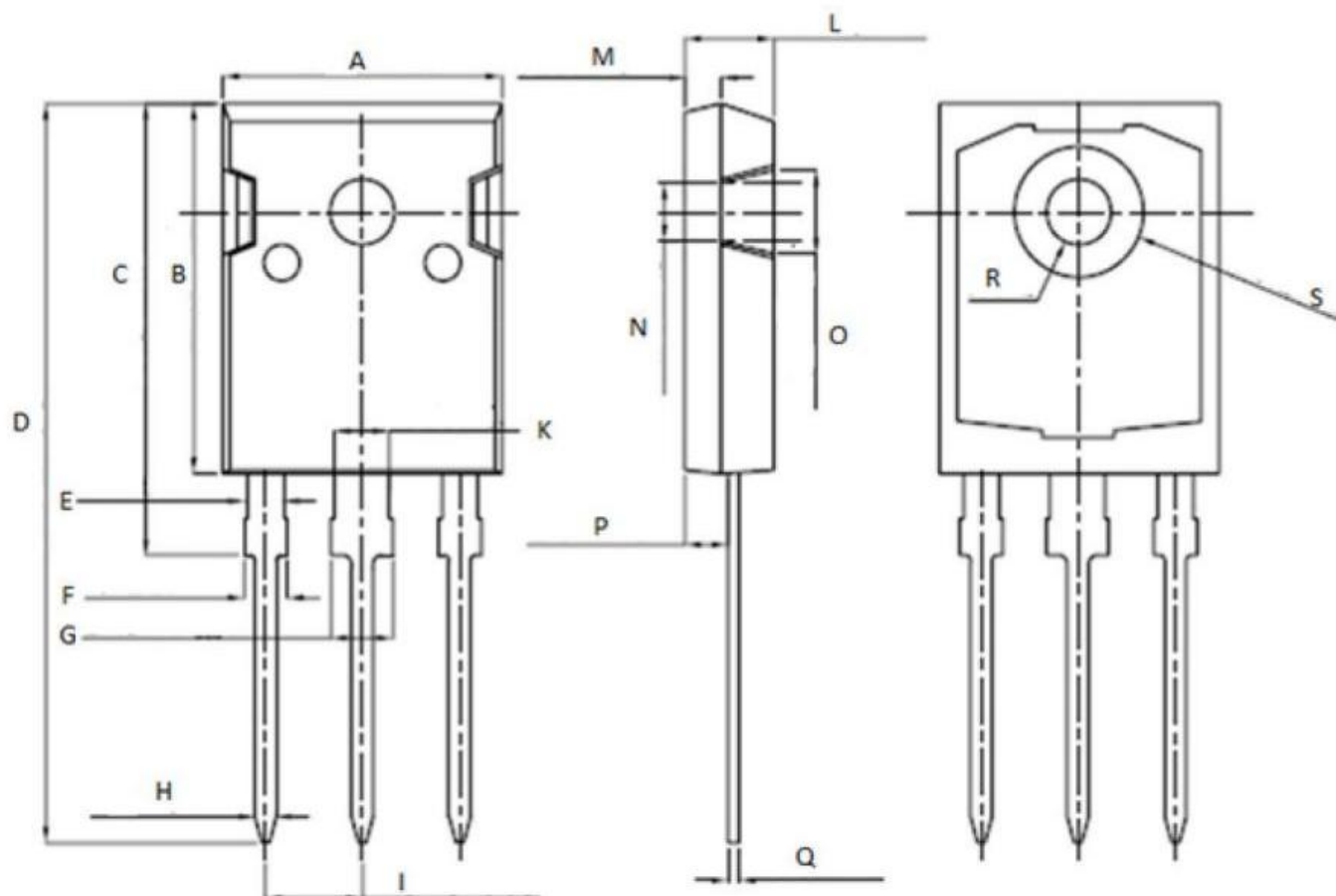


Fig 18. Diode recovery

Package outline drawing(TO-247 Unit: mm)



| Unit: mm | | |
|----------|-------|-------|
| Symbol | Min. | Max. |
| A | 15.95 | 16.25 |
| B | 20.85 | 21.25 |
| C | 20.95 | 21.35 |
| D | 40.5 | 40.9 |
| E | 1.9 | 2.1 |
| F | 2.1 | 2.25 |
| G | 3.1 | 3.25 |
| H | 1.1 | 1.3 |
| I | 5.40 | 5.50 |

| Unit: mm | | |
|----------|-------|-------|
| Symbol | Min. | Max. |
| K | 2.90 | 3.10 |
| L | 4.90 | 5.30 |
| M | 1.90 | 2.10 |
| N | 4.50 | 4.70 |
| O | 5.40 | 5.60 |
| P | 2.29 | 2.49 |
| Q | 0.51 | 0.71 |
| R | φ 3.5 | φ 3.7 |
| S | φ 7.1 | φ 7.3 |

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